	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
1	IS&R	2	("6397361").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 11:25		
2	BRS	84	chip-to-package	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 09:14		
3	BRS	337	test$3 with semiconductor$1 with i/o	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 09:44		
4	BRS	5196	324/713,763,765,538,711.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/18 17:18		
5	BRS	773	702/117,118.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/18 17:18		

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
6	BRS	4	(test$3 or detect$3) with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or wafer$1 or (integrated adj circuit$1)) and (differen$2 or compar$4) with (threshold$1 or predetermined or reference) and (switch$3 or latch$2) and package$1 with chip$1 and driver$1 with receiver$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/18 17:20		
7	BRS	837	702/117,118.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/18 17:18		
8	BRS	5406	324/713,763,765,538,711.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/18 17:18		

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
9	BRS	5	(test$3 or detect$3) with connect$5 with (I/O or input/output) with (semiconductor$1 or IC$1 or wafer$1 or (integrated adj circuit$1)) and (differen$2 or compar$4) with (threshold$1 or predetermined or reference) and (switch$3 or latch$2) and package$1 with chip$1 and driver$1 with receiver$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/18 17:21		
10	BRS	2	"20040153276"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 08:13		
11	IS&R	16	(("6058496") or ("5923676") or ("5502392") or ("5278841") or ("5265901") or ("5736862") or ("5268645") or ("4565966")).PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 10:40		
12	BRS	33	324/$.ccls. and tang.xp.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 09:27		

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
13	BRS	367	test$3 with semiconductor$1 with i/o	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 09:44		
14	BRS	1589	test$3 with semiconductor$1 with (input adj output or i/o)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 09:45		
15	BRS	0	test$3 with semiconductor$1 with (input adj output or i/o) and connect$5 with chip$1 with package41	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 09:46		
16	BRS	93	test$3 with semiconductor$1 with (input adj output or i/o) and connect$5 with chip$1 with package$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 09:46		
17	BRS	3	test$3 with semiconductor$1 with (input adj output or i/o) and connect$5 with chip$1 with package$1 and (start$3 or initiz$5) with (latch$3 or switch$) with transition$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 09:48		

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	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
18	BRS	7	test$3 with semiconductor$1 with (input adj output or i/o) and connect$5 with chip$1 with package$1 and (start$3 or initiz$5) with (latch$3 or switch$)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 09:51		
19	BRS	4	test$3 with semiconductor$1 with (input adj output or i/o) and connect$5 with chip$1 with package$1 and (latch$3 or switch$) with (threshold$1 or desired or predetermin$2 expect$2 or preset$4 or predefin$2) with transition	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 09:52		
20	BRS	19	test$3 with semiconductor$1 with (input adj output or i/o) and connect$5 with chip$1 with package$1 and (latch$3 or switch$) with (threshold$1 or desired or predetermin$2 expect$2 or predetermin$2 or preset$4 or predefin$2)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 09:53		

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
21	BRS	13	test$3 with semiconductor$1 with (input adj output or i/o) and connect$5 with chip$1 with package$1 and (latch$3 or switch$) with (threshold$1 or desired or predetermin$2 expect$2 or preset$4 or predefin$2) and transition	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 09:56		
22	BRS	4	test$3 with semiconductor$1 with (input adj output or i/o) and connect$5 with chip$1 with package$1 and transition with reach$3 with (threshold$1 or desired or expect$2 or predetermin$2 or preset$4 or predefin$2)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 09:57		
23	BRS	4	test$3 with semiconductor$1 with (input adj output or i/o) and transition with reach$3 with (threshold$1 or desired or expect$2 or predetermin$2 or preset$4 or predefin$2)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 13:09		

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
24	BRS	4	test$3 with semiconductor$1 with (input adj output or i/o) and connect$5 with chip$1 with package$1 and transition with (threshold$1 or desired or expect$2 or predetermin$2 or preset$4 or predefin$2)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 09:58		
25	BRS	34	test$3 with semiconductor$1 with (input adj output or i/o) and transition with (threshold$1 or desired or expect$2 or predetermin$2 or preset$4 or predefin$2)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 09:58		
26	IS&R	2	("6260163").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 10:39		
27	IS&R	2	("6020752").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 10:39		
28	IS&R	2	("5602989").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 10:39		

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	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
29	IS&R	2	("5241264").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 10:40		
30	IS&R	8	(("6058496") or ("5923676") or ("5736862") or ("5502392") or ("5278841") or ("5268645") or ("5265901") or ("4565966")).PN.	USPAT	2004/10/19 10:40		
31	IS&R	2	("6262580").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 11:37		
32	BRS	4	test$3 with semiconductor$1 with (input adj output or i/o) and impedance with connection with driver$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 13:10		
33	BRS	4	test$3 with semiconductor$1 with (input adj output or i/o) and imped$4 with connection with driver$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 13:11		
34	BRS	2	test$3 with semiconductor$1 with (input adj output or i/o) and additional with imped$4 with connect$3 with driver$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/19 13:11		

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